

# International IOR Rectifier

PD -90930B

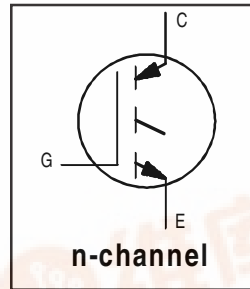
## IRGIH50F

INSULATED GATE BIPOLAR TRANSISTOR

Fast Speed IGBT

### Features

- Electrically Isolated and Hermetically Sealed
- Simple Drive Requirements
- Latch-proof
- Fast Speed operation 3 kHz - 8 kHz
- High operating frequency
- Switching-loss rating includes all "tail" losses

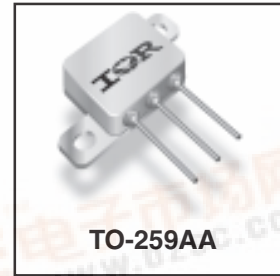


$V_{CES} = 1200V$
$V_{CE(on) \max} = 2.9V$
@ $V_{GE} = 15V, I_C = 25A$

### Description

Insulated Gate Bipolar Transistors (IGBTs) from International Rectifier have higher usable current densities than comparable bipolar transistors, while at the same time having simpler gate-drive requirements of the familiar power MOSFET. They provide substantial benefits to a host of high-voltage, high-current applications.

The performance of various IGBTs varies greatly with frequency. Note that IR now provides the designer with a speed benchmark ( $f_{IC/2}$ , or the "half-current frequency"), as well as an indication of the current handling capability of the device.



### Absolute Maximum Ratings

	Parameter	Max.	Units
$V_{CES}$	Collector-to-Emitter Breakdown Voltage	1200	V
$I_C @ T_C = 25^\circ C$	Continuous Collector Current	45	A
$I_C @ T_C = 100^\circ C$	Continuous Collector Current	25	
$I_{CM}$	Pulsed Collector Current ①	180	
$I_{LM}$	Clamped Inductive Load Current ②	90	
$V_{GE}$	Gate-to-Emitter Voltage	$\pm 20$	V
$P_D @ T_C = 25^\circ C$	Maximum Power Dissipation	200	W
$P_D @ T_C = 100^\circ C$	Maximum Power Dissipation	80	
$T_J$	Operating Junction and Storage Temperature Range	-55 to + 150	$^\circ C$
$T_{STG}$			
	Lead Temperature	300 (0.063in./1.6mm from case for 10s)	
	Weight	10.5 (typical)	g

### Thermal Resistance

	Parameter	Min	Typ	Max	Units	Test Conditions
$R_{thJC}$	Junction-to-Case	—	—	0.625	$^\circ C/W$	
$R_{thCS}$	Case-to-Sink	—	0.21	—		
$R_{thJA}$	Junction-to-Ambient	—	—	30		

For footnotes refer to the last page  
www.irf.com



**Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)**

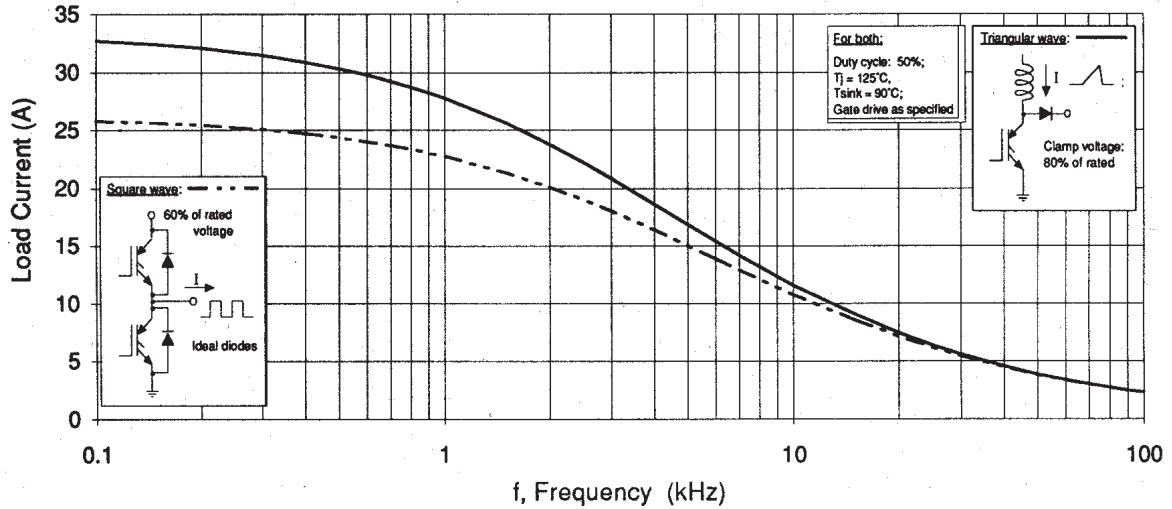
	Parameter	Min.	Typ.	Max.	Units	Conditions
V <sub>(BR)CES</sub>	Collector-to-Emitter Breakdown Voltage	1200	—	—	V	V <sub>GE</sub> = 0V, I <sub>C</sub> = 100 μA
V <sub>(BR)ECS</sub>	Emitter-to-Collector Breakdown Voltage ③	22	—	—	V	V <sub>GE</sub> = 0V, I <sub>C</sub> = 1.0 A
ΔV <sub>(BR)CES/ΔT<sub>J</sub></sub>	Temperature Coeff. of Breakdown Voltage	—	1.1	—	V/°C	V <sub>GE</sub> = 0V, I <sub>C</sub> = 1.0 mA
V <sub>CE(ON)</sub>	Collector-to-Emitter Saturation Voltage	—	2.1	2.9	V	I <sub>C</sub> = 25A V <sub>GE</sub> = 15V
		—	2.5	—		I <sub>C</sub> = 45A See Fig.2, 5
		—	2.4	—		I <sub>C</sub> = 25A, T <sub>J</sub> = 125°C
V <sub>GE(th)</sub>	Gate Threshold Voltage	3.0	—	5.5		V <sub>CE</sub> = V <sub>GE</sub> , I <sub>C</sub> = 250 μA
ΔV <sub>GE(th)/ΔT<sub>J</sub></sub>	Temperature Coeff. of Threshold Voltage	—	-14	—	mV/°C	V <sub>CE</sub> = V <sub>GE</sub> , I <sub>C</sub> = 250 μA
g <sub>fe</sub>	Forward Transconductance ④	7.5	—	—	S	V <sub>CE</sub> = 100V, I <sub>C</sub> = 25A
I <sub>CES</sub>	Zero Gate Voltage Collector Current	—	—	100	μA	V <sub>GE</sub> = 0V, V <sub>CE</sub> = 960V
		—	—	1200		V <sub>GE</sub> = 0V, V <sub>CE</sub> = 960V, T <sub>J</sub> = 125°C
I <sub>GES</sub>	Gate-to-Emitter Leakage Current	—	—	±100	nA	V <sub>GE</sub> = ±20V

**Switching Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)**

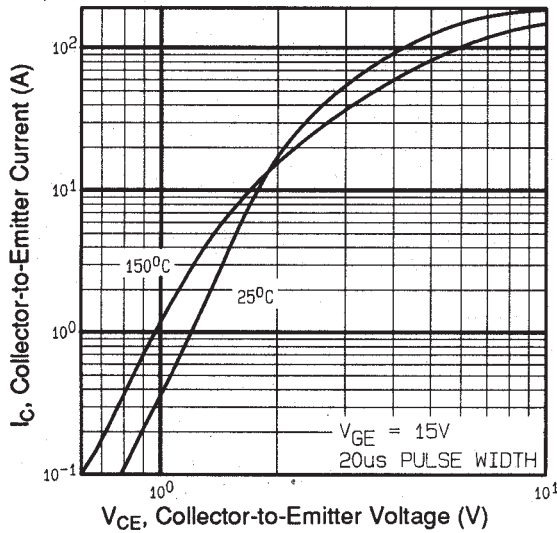
	Parameter	Min.	Typ.	Max.	Units	Conditions
Q <sub>g</sub>	Total Gate Charge (turn-on)	—	—	100	nC	I <sub>C</sub> = 25A
Q <sub>ge</sub>	Gate - Emitter Charge (turn-on)	—	—	21		V <sub>CC</sub> = 400V See Fig. 8 ⑤
Q <sub>gc</sub>	Gate - Collector Charge (turn-on)	—	—	43		V <sub>GE</sub> = 15V
t <sub>d(on)</sub>	Turn-On Delay Time	—	—	68	ns	I <sub>C</sub> = 25A, V <sub>CC</sub> = 400V
t <sub>r</sub>	Rise Time	—	—	26		V <sub>GE</sub> = 15V, R <sub>G</sub> = 2.35Ω ⑤
t <sub>d(off)</sub>	Turn-Off Delay Time	—	—	480		Energy losses include "tail"
t <sub>f</sub>	Fall Time	—	—	330		See Fig. 9, 10, 14
E <sub>on</sub>	Turn-On Switching Loss	—	1.4	—		mJ
E <sub>off</sub>	Turn-off Switching Loss	—	4.5	—		
E <sub>ts</sub>	Total Switching Loss	—	5.9	8.2		
t <sub>d(on)</sub>	Turn-On Delay Time	—	33	—	ns	T <sub>J</sub> = 125°C
t <sub>r</sub>	Rise Time	—	15	—		I <sub>C</sub> = 25A, V <sub>CC</sub> = 400V
t <sub>d(off)</sub>	Turn-Off Delay Time	—	590	—		V <sub>GE</sub> = 15V, R <sub>G</sub> = 2.35Ω ⑤
t <sub>f</sub>	Fall Time	—	500	—		Energy losses include "tail"
E <sub>ts</sub>	Total Switching Loss	—	13	—		mJ See Fig. 11, 14
L <sub>C+LE</sub>	Total Inductance	—	6.8	—	nH	Measured from Collector lead (6mm/0.25in. from package) to Emitter lead (6mm / 0.25in. from package)
C <sub>ies</sub>	Input Capacitance	—	2400	—	pF	V <sub>GE</sub> = 0V
C <sub>oes</sub>	Output Capacitance	—	140	—		V <sub>CC</sub> = 30V See Fig. 7
C <sub>res</sub>	Reverse Transfer Capacitance	—	28	—		f = 1.0MHz

**Note: Corresponding Spice and Saber models are available on the Website.**

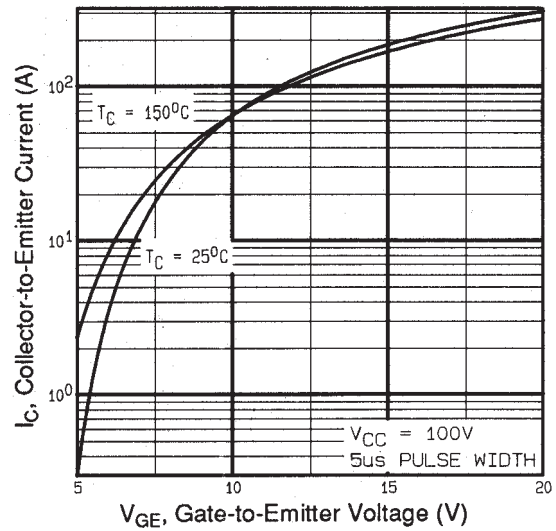
For footnotes refer to the last page



**Fig. 1 - Typical Load Current vs. Frequency**  
(For square wave,  $I = I_{\text{RMS}}$  of fundamental; for triangular wave,  $I = I_{\text{PK}}$ )



**Fig. 2 - Typical Output Characteristics**



**Fig. 3 - Typical Transfer Characteristics**

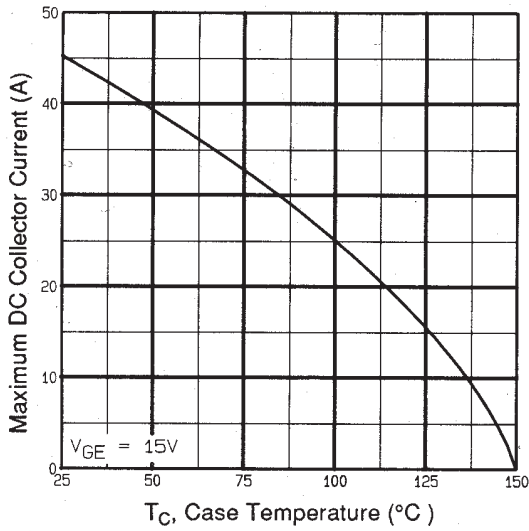


Fig. 4 - Maximum Collector Current vs. Case Temperature

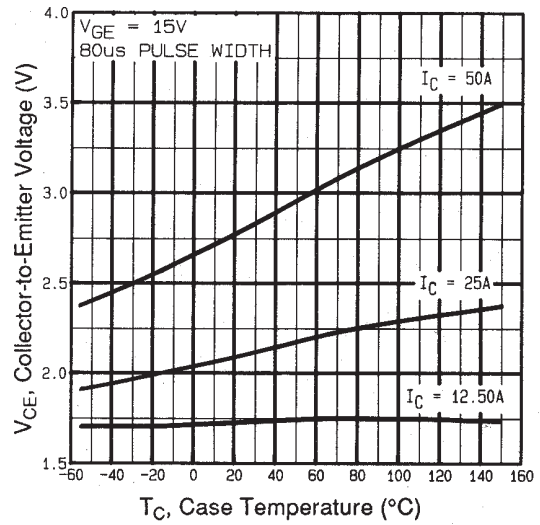


Fig. 5 - Collector-to-Emitter Voltage vs. Junction Temperature

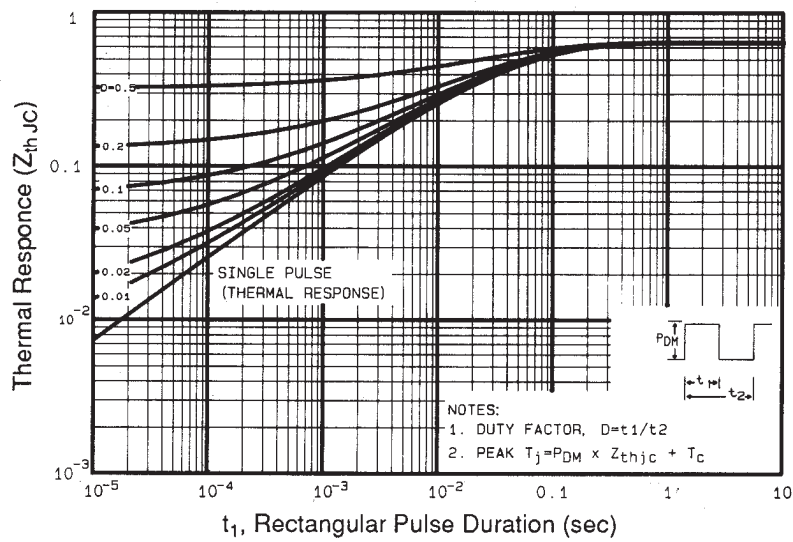


Fig. 6 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

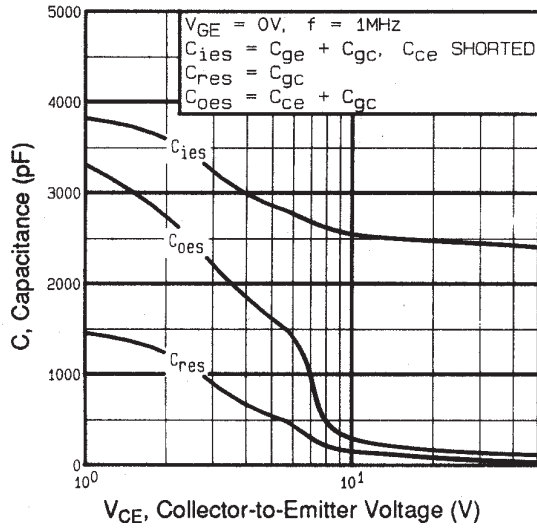


Fig. 7 - Typical Capacitance vs. Collector-to-Emitter Voltage

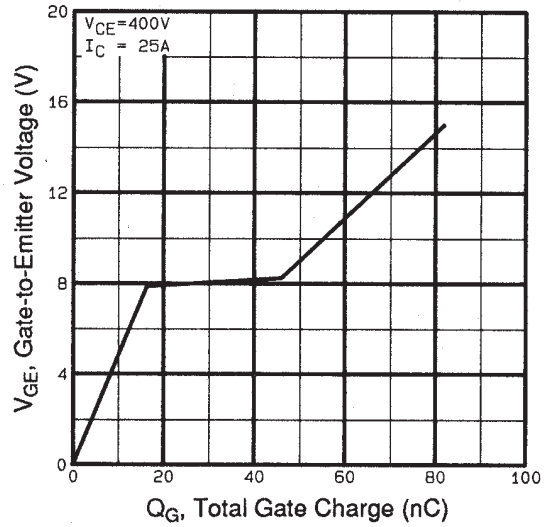


Fig. 8 - Typical Gate Charge vs. Gate-to-Emitter Voltage

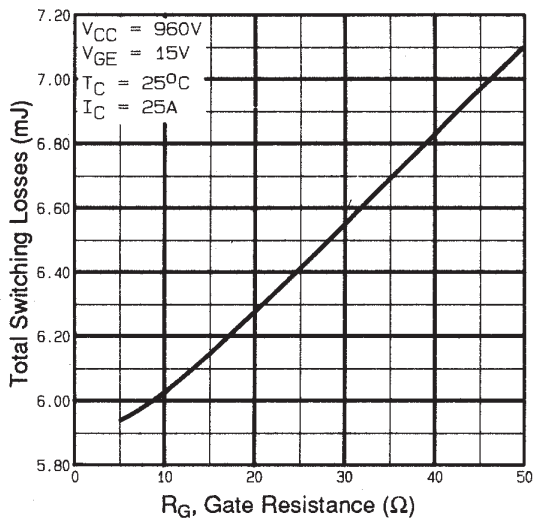


Fig. 9 - Typical Switching Losses vs. Gate Resistance

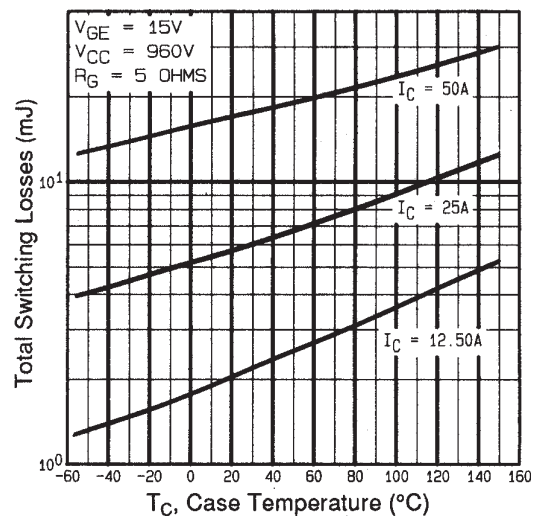


Fig. 10 - Typical Switching Losses vs. Junction Temperature

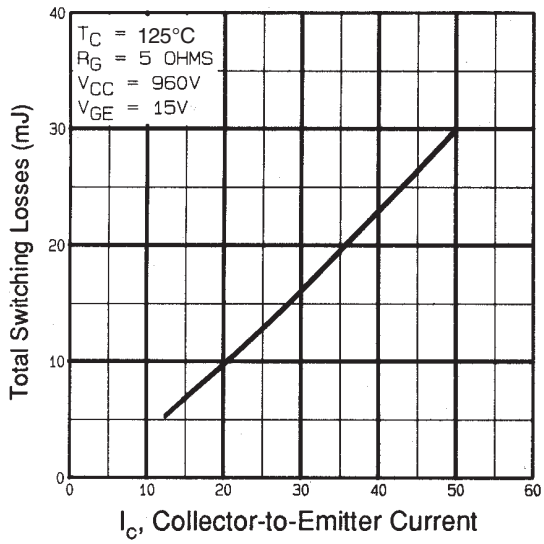


Fig. 11 - Typical Switching Losses vs. Collector-to-Emitter Current

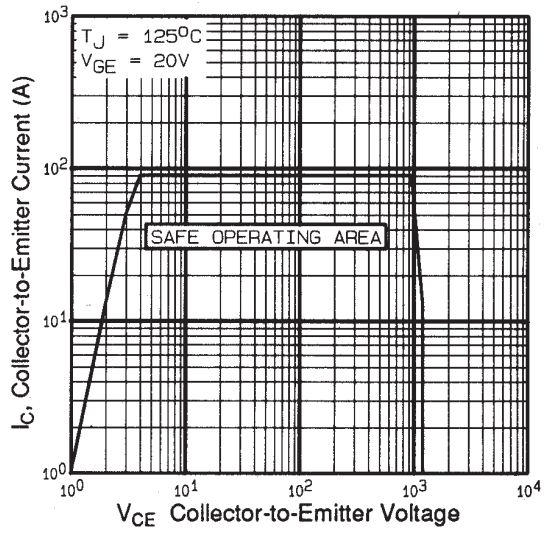
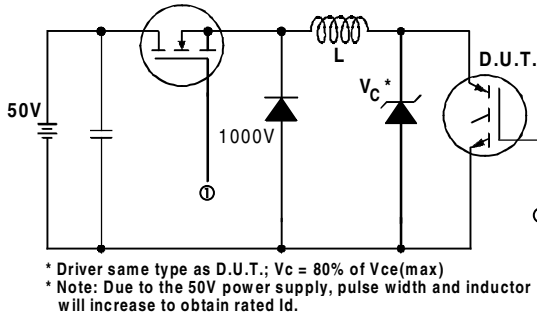
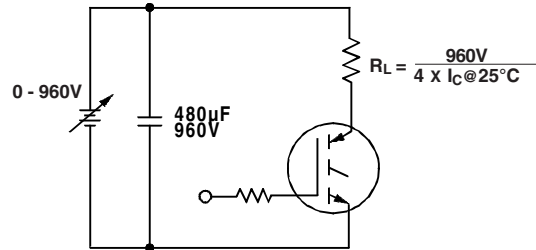


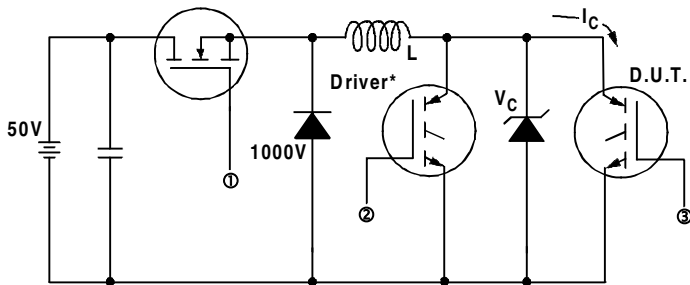
Fig. 12 - Turn-Off SOA



**Fig. 13a** - Clamped Inductive Load Test Circuit

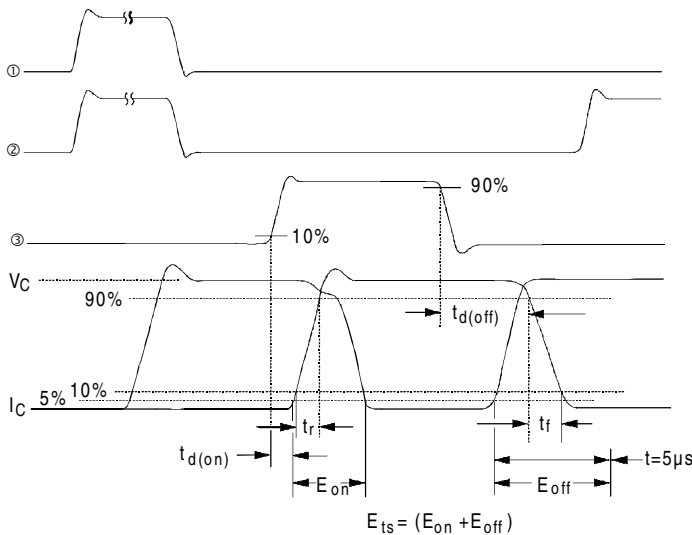


**Fig. 13b** - Pulsed Collector Current Test Circuit



**Fig. 14a** - Switching Loss Test Circuit

\* Driver same type as D.U.T.,  $V_C = 960V$



**Fig. 14b** - Switching Loss Waveforms

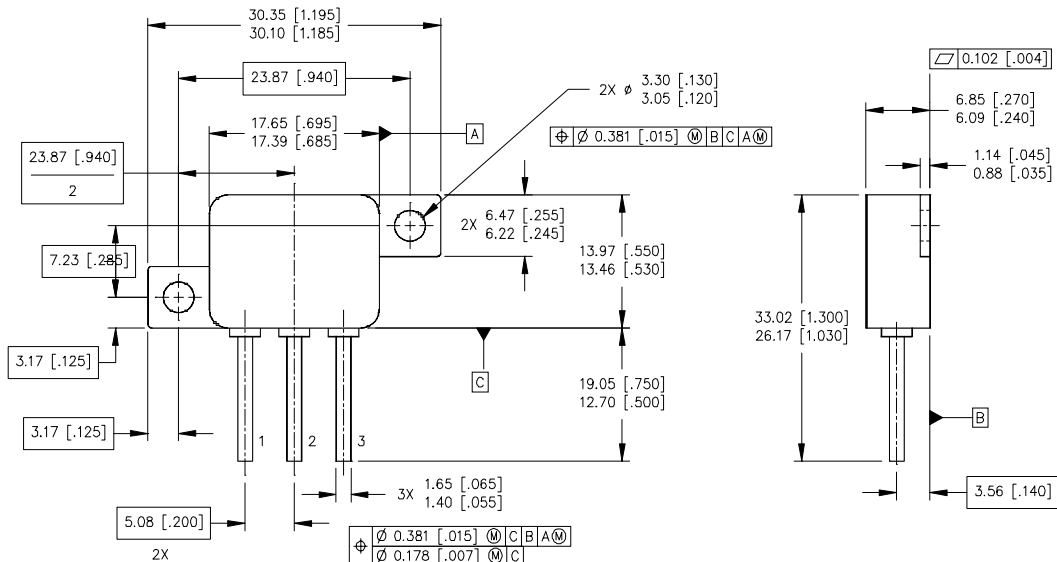
# IRGIH50F

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## Notes:

- ① Repetitive rating;  $V_{GE} = 20V$ , pulse width limited by max. junction temperature.
- ②  $V_{CC} = 80\%(V_{CES})$ ,  $V_{GE} = 20V$ ,  $L = 10\mu H$ ,  $R_G = 5.0\Omega$
- ③ Pulse width  $\leq 80\mu s$ ; duty factor  $\leq 0.1\%$ .
- ④ Pulse width  $5.0\mu s$ , single shot.
- ⑤ Equipment limitation.

## Case Outline and Dimensions — TO-259AA



## NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME 14.5M-1994.
2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
3. CONTROLLING DIMENSION: INCH
4. CONFORMS TO JEDEC OUTLINE TO-259AA.

## LEGEND

- 1 = COLLECTOR
- 2 = EMITTER
- 3 = GATE

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